Notice of References Cited

Application/Control No 09/955,804

Applicant(s)/Patent Under Reexamination PAVELA, THOMAS J.

Examiner Ted T. Vo Art Unit 2122

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-5,754,755	05-1998	Smith, Jr., Ross Faulkner	714/38
	В	US-6,332,211 B1	12-2001	Pavela, Thomas J.	717/130
	С	US-			
	D	US-			
	Ε	US-			
	F	US-			
	G	US-		· ·	
	Н	US-			
	1	US-			
	J	US-			
	κ	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N				,	
	0					
	Р					
	Q	•			·	
	R					
	s					
	Т					

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
	Ų	IBM Technical Disclosure Bulletin, "FACTOR (Fairchild Sentry VIII Tester Language) SYNTAX Checker/Analyzer", vol. 28, No. 7, pages: 3140-3144, 12-1985.					
	v	Naiknaware, "Analog Automatic Test Plan Generator – Intergrating with Modular Analog IC Design Environment", IEEE, pages: 318-321, 10-1993.					
	w						
	x						

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

U.S. Patent and Trademark Office PTO-892 (Rev. 01-2001)

Notice of References Cited

Part of Paper No. 5